

10/568842

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APS Rec'd PCT/PTO 17 FEB 2006

Applicant: Michael Goessel et al.  
Serial No.: Unknown  
(Priority Application No. DE 103 38 922.9)  
(International Application No. PCT/DE2004/001799)  
Filed: Herewith  
(Priority Date August 20, 2003)  
(International Filing Date August 11, 2004)  
Docket No.: I431.151.101/FIN 504 PCT  
Title: ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE  
TESTING AND/OR THE DIAGNOSTIC ANALYSIS OF AN  
INTEGRATED CIRCUIT

---

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached form 1449 be considered by the Examiner and made of record. Any required copies of patents, publications or other documents are enclosed for the Examiner's review. Pursuant to the provisions of M.P.E.P. 609, Applicants further request a copy of the 1449 form, marked as being considered and initialed by the Examiner, be returned with the next Official Communication.

Since this Information Disclosure Statement is being submitted within three months of filing national application; or date of entry of national application; or before the mailing date of the first Office Action on the merits, a fee has not been enclosed. However, if such fee is required, the Patent Office is hereby authorized to charge Deposit Account No. 500471 for fees as set forth under 37 C.F.R. 1.17(p).

**Information Disclosure Statement**

Applicant: Michael Goessel et al.

Serial No.: Unknown

(Priority Application No. DE 103 38 922.9)

(International Application No. PCT/DE2004/001799)

Filed: Herewith

(Priority Date: August 20, 2003)

(International Filing Date: August 11, 2004)

Docket No.: I431.151.101/FIN 504 PCT

Title: ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE TESTING AND/OR THE  
DIAGNOSTIC ANALYSIS OF AN INTEGRATED CIRCUIT

10/ 568842  
IAP5 Rec'd PCT/PTO 17 FEB 2006

Applicants respectfully request consideration of these references during prosecution of the above-identified matter. The Examiner is invited to contact the Applicants' representative at the below-listed telephone number if there are any questions regarding this Communication or the tendered references.

Respectfully submitted,

Michael Goessel et al.,

By their attorneys,

DICKE, BILLIG & CZAJA, PLLC  
Fifth Street Towers, Suite 2250  
100 South Fifth Street  
Minneapolis, MN 55402  
Telephone: (612) 573-2002  
Facsimile: (612) 573-2005

Dated: February 17, 2006  
SED:jan

Steven E. Dicke  
Steven E. Dicke  
Reg. No. 38,431

**CERTIFICATE UNDER 37 C.F.R. 1.10:**

"Express Mail" mailing label number: EV309842854US

Date of Deposit: February 17, 2006

The undersigned hereby certifies that this paper or papers, as described herein, are being deposited in the United States Postal Service "Express Mail Post Office to Addressee" service under 37 C.F.R. 1.10 on the date indicated above and is addressed to: Mail Stop PCT, Commissioner for Patents, P.O. Box 1450/Alexandria, VA 22313-1450.

By

Vanessa Carels  
Name: Vanessa Carels

FORM PTO-1449	Docket No.: I431.151.101/FIN 504 PCT		Serial No.: Unknown Priority Appln. No. DE 103 38 922.9 Int'l Appln. No. PCT/DE2004/001799
	<b>10/568842</b>		
	Applicant: Michael Goessel et al.		
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Filing Date: Herewith Priority Date 20 August 2003 Int'l Filing Date 11 August 2004		Group Art: Unknown

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
	4,503,537	03/1985	McAnney			
	4,601,034	07/1986	Sridhar			
	5,081,626	01/1992	Scott			
	5,230,000	07/1993	Mozingo et al.			
	5,574,733	11/1996	Kim			
	5,745,500	04/1998	Damarla et al.			
	5,831,992	11/1998	Wu			
	5,930,270	07/1999	Forlenza et al.			
	6,055,660	04/2000	Meaney			
	6,158,033	12/2000	Wagner et al.			
	6,442,723	08/2002	Koprowski et al.			
	6,510,398	01/2003	Kundu et al.			

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translated Yes No
	19929546	09/2000	DE			Yes (Abstract Only)
	01/38889	05/2001	PCT			Yes
						Yes

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	✓	Laung-Terng Wang, "Autonomous Linear Feedback Shift Register with On-Line Fault-Detection Capability", 1982 IEEE, XP 000746113, pgs. 311-314.
	✓	IBM Technical Disclosure Bulletin, "Reconfigurable Linear Feedback Shift Register", Vol. 34 No. 6 November 1991, XP 000212785, pgs. 377-380.
	✓	P.H. Bardell, W.H. Mc Anney und J. Savir, "Built-In Test for VLSI: Pseudorandom Techniques", New York, 1987, pgs. 285-287.
	✓	M. Abromovici, M.A. Breuer, A.D. Friedman; "Digital Systems Testing and Testable Design", Computer Science Press, pgs. 365-382.
	✓	L. Voelkel, J. Pliquet; "Theore-tische Grundlagen und Probleme - Ausblick und Anwendungen"; Akade-mie-Verlag Berlin 1988 Standard Literature.
	✓	Shu Lin, D.J. Costello; "Error Control Coding, Fundamentals and Applications", New Jersey 07632 pgs. 79-85.
	✓	Gerner, M. Muller, B.: Sandweg, G.: "Selbsttest digitaler Schaltungen. Munchen (u.a.): Oldenbourg, 1990, p. 100-117, 140-151.
	✓	Internet Page <a href="http://www.adobe.com/products/acrobat/readste2.html">http://www.adobe.com/products/acrobat/readste2.html</a> of December 17, 2001 (reconstructed by <a href="http://www.archive.org">http://www.archive.org</a> )

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.